**LIST OF REFERENCES CITED BY APPLICANT**  
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ATTY DOCKET NO.

060937-0178

APPLICATION NO

10/802,780

APPLICANT

Robert J. SMALL

FILING DATE

march 18, 2004

GROUP

1792

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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/MLP/	A01	3,848,258	11/1974	Mahoney et al.			
	A02	3,893,131	07/1975	Perel et al.			
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							YES	NO
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/MLP/	C01	Journal of Vacuum Science & Technology B, "Dry Surface Cleaning Using CO <sub>2</sub> Snow" by Sherman et al., July/august 1991, pp 1970-1977
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EXAMINER

/Marianne L. Padgett/

DATE CONSIDERED

10/29/2007

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

## LIST OF REFERENCES CITED BY APPLICANT

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ATTY DOCKET NO.

060937-0179

APPLICATION NO

~~10/361,822~~

APPLICANT Robert Small

~~Brandon Shane SCOTT et al.~~

FILING DATE 3/18/2004

GROUP 1792

~~February 11, 2003~~~~1755~~

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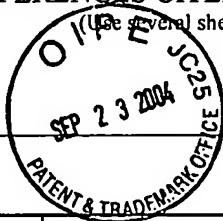
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	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
						YES NO
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	B02					

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

/MLP/	C01	"Mechanistic Aspects of Chemical mechanical Polishing of tungsten Using Ferric Ion Based Alumina Slurries" by Raghunath et al., ESP, Vol. 96-22, pp. 1-15 (no date-based on cites, 1996 or later)
/MLP/	C02	"Electrochemical Aspects of the Chemical Mechanical Planarization of Tungsten" by Basak et al., ESP Vol. 96-22, pp. 137-148 (no date-based on citations, 1996 or later)

<b>LIST OF REFERENCES CITED BY APPLICANT</b> (Use several sheets if necessary)	ATTY DOCKET NO.	APPLICATION NO <u>10/361,822</u>
	APPLICANT <b>Robert Small</b> <del>Brandon Shane SCOTT et al.</del>	
	FILING DATE <del>February 11, 2003</del> 3/18/2004	GROUP AU 1792



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	B02							
	B03							
	B04							
	B05							

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	C01	
	C02	
	C03	

EXAMINER	/Marianne L. Padgett/	DATE CONSIDERED	10/29/2007
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